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Fairchild Semiconductor FDG315N

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July 2000

FDG315N

N-Channel Logic Level PowerTrench® MOSFET

General Description

This N-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

Applications

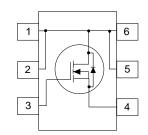
- DC/DC converter
- Load switch
- Power Management

Features

• 2 A, 30 V.
$$R_{DS(ON)} = 0.12~\Omega~$$
 @ $V_{GS} = 10~V$
$$R_{DS(ON)} = 0.16~\Omega~$$
 @ $V_{GS} = 4.5~V.$

- Low gate charge (2.1nC typical).
- \bullet High performance trench technology for extremely low $R_{\text{\tiny DS/(ON)}}.$
- Compact industry standard SC70-6 surface mount package.





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DSS}	Drain-Source Voltage		30	V
V_{GSS}	Gate-Source Voltage		±20	V
I_D	Drain Current - Continuous	(Note 1a)	2	Α
	- Pulsed		6	
P_{D}	Power Dissipation for Single Operation	(Note 1a)	0.75	W
		(Note 1b)	0.48	
T _J , T _{stq}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

Ra	Thermal Resistance, Junction-to-Ambient	(Note 1b)	260	°C/W
L A IV	I THEITIAI NESISIANCE, JUNCUOTI-IU-AITIDIENI	(Note 10)	200	C/ V V

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
. 15	FDG315N	7"	8mm	3000 units



Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					'
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		26		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate-Body Leakage Forward	V _{GS} = 16 V, V _{DS} = 0 V			100	nA
I _{GSS}	Gate-Body Leakage Reverse	$V_{GS} = -16 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	1	1.8	3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-4		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 2 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 2 \text{ A}, T_J = 125^{\circ}\text{C}$ $V_{GS} = 4.5 \text{ V}, I_D = 1.7 \text{ A}$		0.100 0.140 0.130	0.12 0.20 0.16	Ω
I _{D(on)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$	3			Α
G _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 2 \text{ A}$		5		S
Dynamic	: Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$		220		pF
Coss	Output Capacitance	f = 1.0 MHz		50		pF
C _{rss}	Reverse Transfer Capacitance	1		20		pF
Switchin	g Characteristics (Note 2)					
I _{d(on)}	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, I_D = 1 \text{ A},$		3	6	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		11	22	ns
t _{d(off)}	Turn-Off Delay Time	1		7	14	ns
t _f	Turn-Off Fall Time	1		3	6	ns
$\overline{Q_g}$	Total Gate Charge	$V_{DS} = 15 \text{ V}, I_D = 2 \text{ A},$		2.1	4	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 \text{ V}$		0.8		nC
Q _{gd}	Gate-Drain Charge	1		0.7		nC
Drain-Sc	ource Diode Characteristics	and Maximum Ratings	•	•	:	;
l _s	Maximum Continuous Drain-Source				0.42	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 0.42 A (Note 2)		0.7	1.2	V

Notes

^{1.} $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.

a) 170°C/W when mounted on a 1 in $^2 pad$ of 2oz copper.

b) 260°C/W when mounted on a minimum pad.

^{2.} Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%





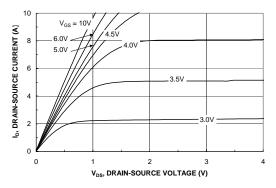


Figure 1. On-Region Characteristics.

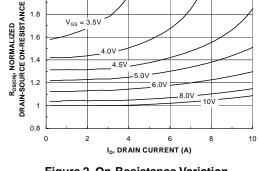


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

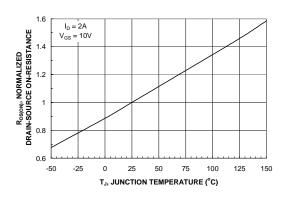


Figure 3. On-Resistance Variation with Temperature.

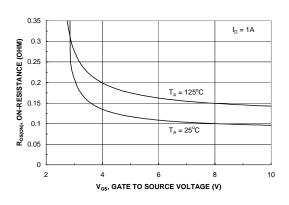


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

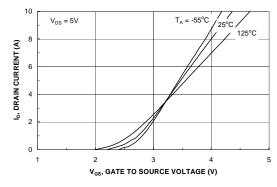


Figure 5. Transfer Characteristics.

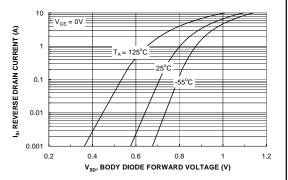
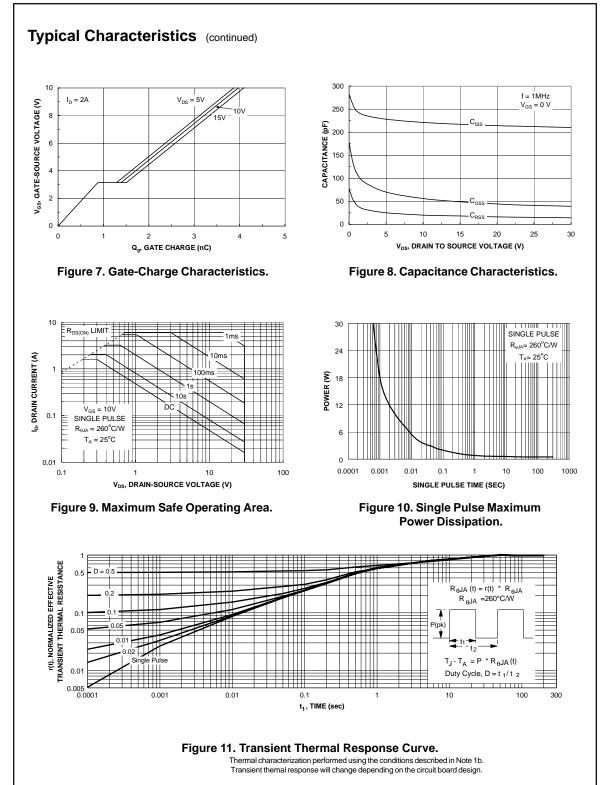


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.







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No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.		
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.		

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